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Space-, Time-, and Energy-Resolved Two-Photon Photoelectron Spectroscopy

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Electron transfer processes at organic-molecule/metal interfaces are important in the development of light emitting diodes and solar cells. Femtosecond time-resolved two-photon photoelectron (TR-2PPE) spectroscopy is a powerful tool to study the ultrafast dynamics of charge carriers on solid surfaces and interfaces. Recently a time-of-flight photoelectron emission microscope (TOF-PEEM) became commercially available, which makes possible a space-resolved TR-2PPE experiment. This report is divided by two parts: (1) ultrafast decay dynamics of the electronics states of Alq₃/Cu interfaces, and (2) space-resolved ultrafast electron relaxation dynamics in Ag-coated Si nanostructures as a demonstration of the first commercial TOF-PEEM.

Ultrafast decay dynamics of the electronic states of Alq₃/Cu interfaces was investigated by interferometric time-resolved two-photon photoelectron spectroscopy. The work function decreased as an increase of Alq₃ thickness. At Alq₃/Cu(111) interface, the anion state lifetime of Alq₃ adsorbed was reported as 31 ± 2 fs by a phase averaged experiment. By the interferometric measurements we studied dephasing and population relaxation dynamics at Alq₃/Cu(111) and Alq₃/Cu(100) interfaces.

Space-resolved ultrafast electron relaxation dynamics in Ag-coated Si nanostructure was investigated by TR-TOF-PEEM. The photoelectron intensity excited by frequency doubled 400 nm of Ti:sapphire laser is enhanced at a topographical edge, the spectrum of which was characterized by the lower work function. Time-resolved spectra between the edges and other flat areas were compared.

[References]

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